

FEB 14 2003

FORM PTO-1449/A and B (Modified)

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT*filed after final rejection*

APPLICATION NO.: 09/361,700

ATTY. DOCKET NO.: S01022.80201.US

FILING DATE: July 27, 1999

CONFIRMATION NO.: 5850

APPLICANT: Pierrick Descure

GROUP ART UNIT: 2811

EXAMINER: Gene M. Munson.

Sheet 1 of 2

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
	1	4,630,091		Kuroda et al.	12-16-1986
	2	5,191,399		Maegawa et al.	03-02-1993
	3	5,306,931		Stevens	04-26-1994
	4	5,330,933		Chan et al.	07-19-1994
	5	5,345,266		Denyer	09-06-1994
	6	5,591,997		Guidash et al.	01-07-1997
	7	5,621,230		Guidash et al.	04-15-1997
	8	5,747,835		Pezzani	05-05-1998
	9	5,831,326		Chan et al.	11-03-1998
	10	5,859,462		Tredwell et al.	01-12-1999
	11	5,881,184		Guidash	03-09-1999
	12	5,903,021		Lee et al.	05-11-1999
	13	5,926,214		Denyer et al.	07-20-1999
	14	5,949,061		Guidash et al.	09-07-1999
	15	5,978,025		Tomasini et al.	11-02-1999
	16	5,981,932		Guerrieri et al.	11-09-1999
	17	5,982,011		Kalnitsky et al.	11-09-1999
	18	5,986,297		Guidash et al.	11-16-1999
	19	6,051,447		Lee et al.	04-18-2000
	20	6,067,113		Hurwitz et al.	05-23-2000
	21	6,069,377		Prentice et al.	05-30-2000
	22	6,087,703		Ohta et al.	07-11-2000
	23	6,100,551		Lee et al.	08-08-2000
	24	6,100,556		Drowley et al.	08-08-2000
	25	6,107,653		Guidash	08-22-2000
	26	6,127,697		Guidash	10-03-2000
	27	6,133,954		Jie et al.	10-17-2000
	28	6,160,281		Guidash	12-12-2000
	29	6,188,056	B1	Kalnitsky et al.	02-13-2001
	30	6,218,656	B1	Guidash	04-17-2001
	31	6,259,124	B1	Guidash	07-10-2001
	32	US 2001/0045580	A1	Descure	11-29-2001
	33	US 2002/0011638	A1	Bordogna et al.	01-31-2002
	34	US 2002/0019070	A1	Laurin et al.	02-14-2002
	35	6,352,876	B1	Bordogna et al.	03-05-2002
	36	US 2002/0030753	A1	Kramer et al.	03-14-2002
	37	6,380,572	B1	Pain et al.	04-30-2002

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

FEB 14 2003

Sheet

of

2

APPLICATION NO.: 09/361,700

ATTY. DOCKET NO.: S01022.80201.US

FILING DATE: July 27, 1999

CONFIRMATION NO.: 5850

APPLICANT: Pierrick Descure

GROUP ART UNIT: 2811

EXAMINER: Gene M. Munson

38

US 2002/0051067

A1

Henderson et al.

05-02-2002

FOREIGN PATENT DOCUMENTS

Examiner's Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/ Country	Number	Kind Code			
	39	EP	1 207 686	A1	STMicroelectronics Limited	05-22-2002	
	40	GB	2 276 512	A	VLSI Vision Limited	09-28-1994	
	41	WO	92/15036	A1	VLSI Vision Limited	09-03-1992	
	42	WO	92/16999	A1	VLSI Vision Limited	10-01-1992	
	43	WO	93/04556	A1	VLSI Vision Limited	03-04-1993	
	44	WO	97/20434	A1	VLSI Vision Limited	06-05-1997	
	45	WO	97/35438	A1	VLSI Vision Limited	09-25-1997	
	46	WO	98/49729	A1	VLSI Vision Limited	11-05-1998	
	47	WO	99/57887	A1	VLSI Vision Limited	11-11-1999	
	48	WO	00/52765	A1	Photobit Corporation	09-08-2000	

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
	49	Patent Abstracts of Japan, vol. 009, no. 061, March 19, 1985 & JP 59 198756 A (Hitachi Seisakusho KK)	Y Abstract
	50	Patent Abstracts of Japan, vol. 1998, no. 02, February 27, 1998 & JP 09 280301 A (Nikon Corp.) November 4, 1997	Y Abstract
	51	Patent Abstracts of Japan, vol. 1998, no. 09, July 31, 1998 & JP 10 098175 A (Toshiba Corp.)	Y Abstract
	52	Patent Abstracts of Japan, vol. 2000, no. 11, January 2, 2001 & JP 2000 236081 A (Nikon Corp.) August 29, 2000	Y Abstract
	53	Furumiya M. et al., "High Sensitivity and No-Cross-Talk Pixel Technology For Embedded CMOS Image Sensor" International Electron Devices Meeting 2000, IEDM, Technical Digest, San Francisco, CA, Dec. 10-13, 2000, New York, NY: IEEE, US, December 10, 2000, pages 701-704	

EXAMINER

G. MUNSON

DATE CONSIDERED

19 MAY 2005

#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.